

LM5050-1 Failure

TW

16Jan/2018

Description:

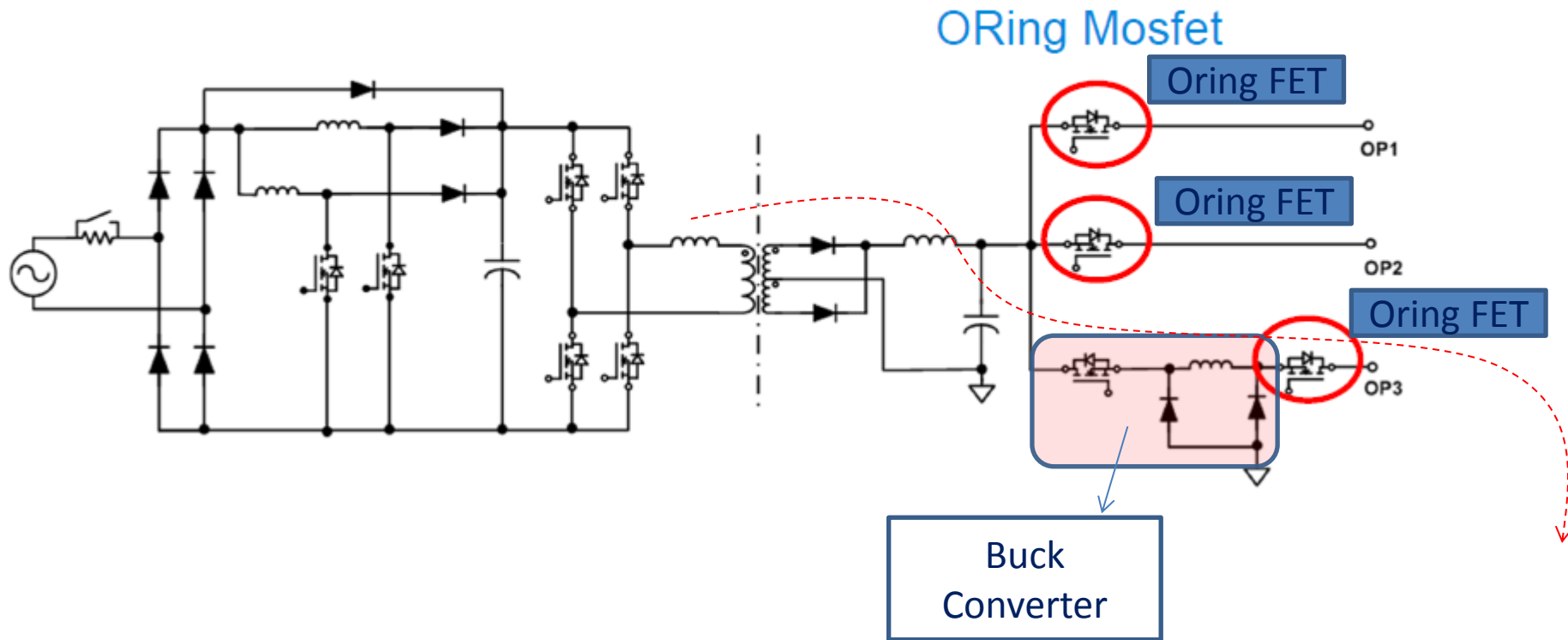
Customer found the devices were damaged during production Testing (power on). The IN, OUT and OFF pin of the LM5050-1 would be damaged and become low impedance. The defective rate is about 30%. The production line is pending now.

After replacing with new device, the behavior is normal.

Working Mode A

OP1 & OP2: Oring Mode

OP3: Oring + Buck Mode

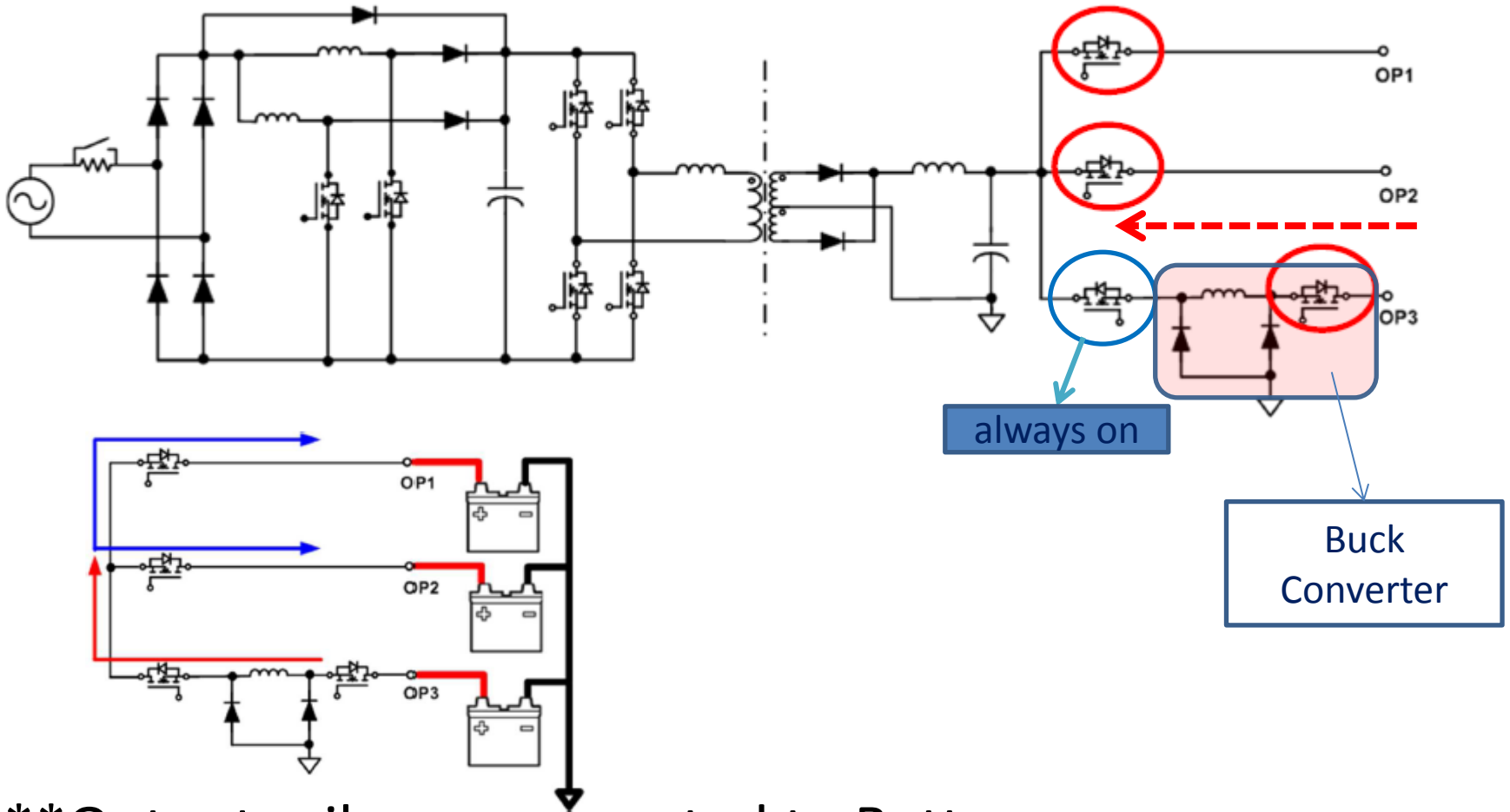


**Output rails are connected to Battery

Working Mode B

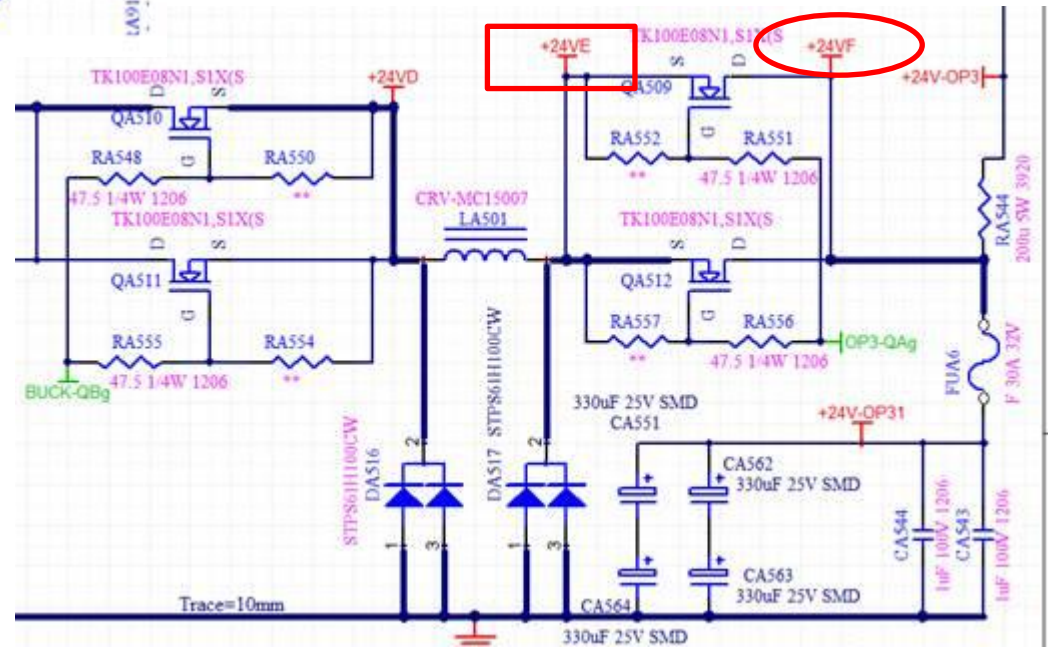
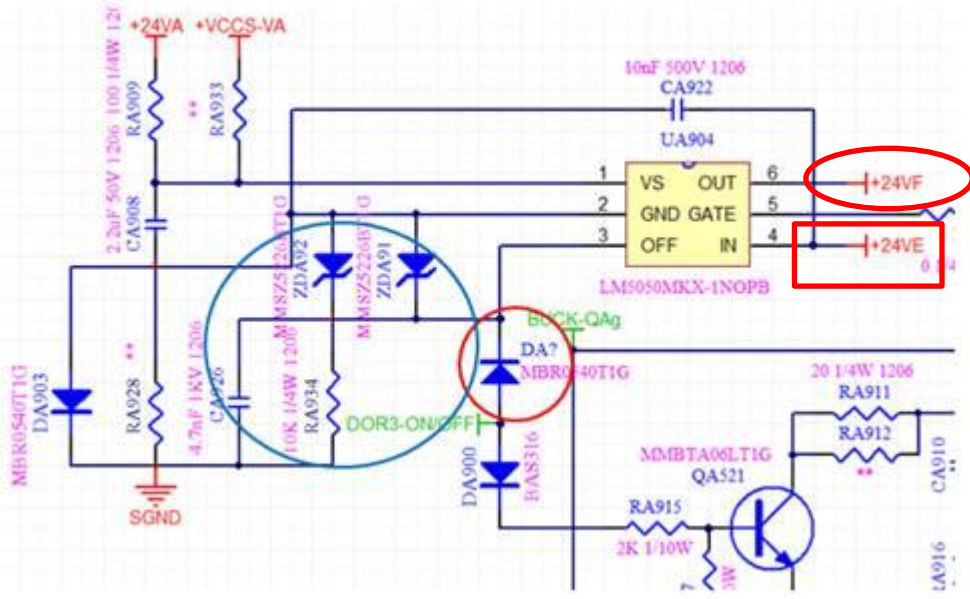
OP1 & OP2: Oring Mode

OP3: Buck Mode



**Output rails are connected to Battery

Schematic



Test Waveform @ BUCK mode



Summary

- From waveform, the voltage stress between the OUT pin and VS pin is 55V. Is that any problem?
- There is a negative 1V between the OFF to GND pin. Is there any problem with OFF pin from stress's point of view?

Summary

- Do you have any suggestion on the schematic to enhance the stress capability?
- We are still trying to figure out the root cause!